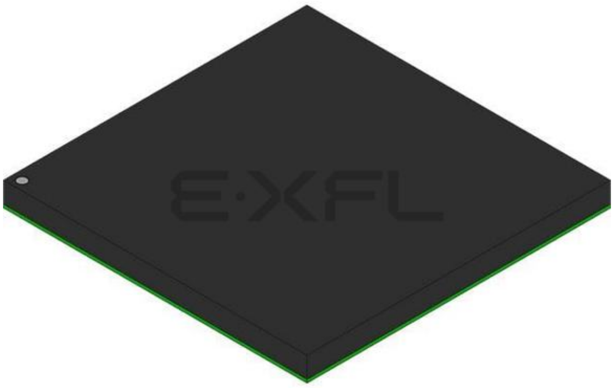
Freescale Semiconductor - MPC8572ELVTAVND Datasheet



Welcome to E-XFL.COM

Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.5GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR2, DDR3
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	1023-BFBGA, FCBGA
Supplier Device Package	1023-FCBGA (33x33)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8572elvtavnd

  the upper and lower words of the 64-bit GPRs as they are defined by the SPE APU.
  - Embedded vector and scalar single-precision floating-point APUs. Provide an instruction set for single-precision (32-bit) floating-point instructions.
  - Double-precision floating-point APU. Provides an instruction set for double-precision (64-bit) floating-point instructions that use the 64-bit GPRs.
  - 36-bit real addressing
  - Memory management unit (MMU). Especially designed for embedded applications. Supports 4-Kbyte to 4-Gbyte page sizes.
  - Enhanced hardware and software debug support
  - Performance monitor facility that is similar to, but separate from, the MPC8572E performance monitor

  The e500 defines features that are not implemented on this device. It also generally defines some features that this device implements more specifically. An understanding of these differences can be critical to ensure proper operation.

- 1 Mbyte L2 cache/SRAM
  - Shared by both cores.
  - Flexible configuration and individually configurable per core.
  - Full ECC support on 64-bit boundary in both cache and SRAM modes
  - Cache mode supports instruction caching, data caching, or both.
  - External masters can force data to be allocated into the cache through programmed memory ranges or special transaction types (stashing).
    - 1, 2, or 4 ways can be configured for stashing only.
  - Eight-way set-associative cache organization (32-byte cache lines)
  - Supports locking entire cache or selected lines. Individual line locks are set and cleared through Book E instructions or by externally mastered transactions.
  - Global locking and Flash clearing done through writes to L2 configuration registers
  - Instruction and data locks can be Flash cleared separately.
  - Per-way allocation of cache region to a given processor.
  - SRAM features include the following:
    - 1, 2, 4, or 8 ways can be configured as SRAM.
    - I/O devices access SRAM regions by marking transactions as snoopable (global).
    - Regions can reside at any aligned location in the memory map.
    - Byte-accessible ECC is protected using read-modify-write transaction accesses for smaller-than-cache-line accesses.
- e500 coherency module (ECM) manages core and intrasystem transactions
- Address translation and mapping unit (ATMU)
  - Twelve local access windows define mapping within local 36-bit address space.
  - Inbound and outbound ATMUs map to larger external address spaces.

  - Supports fully nested interrupt delivery
  - Interrupts can be routed to external pin for external processing.
  - Interrupts can be routed to the e500 core's standard or critical interrupt inputs.
  - Interrupt summary registers allow fast identification of interrupt source.
- Integrated security engine (SEC) optimized to process all the algorithms associated with IPSec, IKE, SSL/TLS, SRTP, 802.16e, and 3GPP
  - Four crypto-channels, each supporting multi-command descriptor chains
    - Dynamic assignment of crypto-execution units through an integrated controller
    - Buffer size of 256 bytes for each execution unit, with flow control for large data sizes
  - PKEU—public key execution unit
    - RSA and Diffie-Hellman; programmable field size up to 4096 bits
    - Elliptic curve cryptography with F_2m and F(p) modes and programmable field size up to 1023 bits
  - DEU—Data Encryption Standard execution unit
    - DES, 3DES
    - Two key (K1, K2, K1) or three key (K1, K2, K3)
    - ECB, CBC and OFB-64 modes for both DES and 3DES
  - AESU—Advanced Encryption Standard unit
    - Implements the Rijndael symmetric key cipher
    - ECB, CBC, CTR, CCM, GCM, CMAC, OFB-128, CFB-128, and LRW modes
    - 128-, 192-, and 256-bit key lengths
  - AFEU—ARC four execution unit
    - Implements a stream cipher compatible with the RC4 algorithm
    - 40- to 128-bit programmable key
  - MDEU—message digest execution unit
    - SHA-1 with 160-bit message digest
    - SHA-2 (SHA-256, SHA-384, SHA-512)
    - MD5 with 128-bit message digest
    - HMAC with all algorithms
  - KEU—Kasumi execution unit
    - Implements F8 algorithm for encryption and F9 algorithm for integrity checking
    - Also supports A5/3 and GEA-3 algorithms
  - RNG—random number generator
  - XOR engine for parity checking in RAID storage applications
  - CRC execution unit
    - CRC-32 and CRC-32C
- Pattern Matching Engine with DEFLATE decompression

4 Input Clocks

4.1 System Clock Timing

Table 6 provides the system clock (SYSCLK) AC timing specifications for the MPC8572E.

Table 6. SYSCLK AC Timing Specifications

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
SYSCLK frequency	f_{SYSCLK}	33	—	133	MHz	1
SYSCLK cycle time	t_{SYSCLK}	7.5	—	30.3	ns	—
SYSCLK rise and fall time	t_{KH}, t_{KL}	0.6	1.0	1.2	ns	2
SYSCLK duty cycle	t_{KHK}/t_{SYSCLK}	40	—	60	%	3
SYSCLK jitter	—	—	—	+/– 150	ps	4, 5, 6

Notes:

1. **Caution:** The CCB clock to SYSCLK ratio and e500 core to CCB clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB clock frequency do not exceed their respective maximum or minimum operating frequencies.Refer to Section 19.2, “CCB/SYSCLK PLL Ratio,” and Section 19.3, “e500 Core PLL Ratio,” for ratio settings.
2. Rise and fall times for SYSCLK are measured at 0.6 V and 2.7 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The SYSCLK driver’s closed loop jitter bandwidth should be <500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track SYSCLK drivers with the specified jitter.
6. For spread spectrum clocking, guidelines are +0% to –1% down spread at a modulation rate between 20 kHz and 60 kHz on SYSCLK.

4.2 Real Time Clock Timing

The RTC input is sampled by the platform clock (CCB clock). The output of the sampling latch is then used as an input to the counters of the PIC and the TimeBase unit of the e500. There is no jitter specification. The minimum pulse width of the RTC signal should be greater than 2x the period of the CCB clock. That is, minimum clock high time is $2 \times t_{CCB}$, and minimum clock low time is $2 \times t_{CCB}$. There is no minimum RTC frequency; RTC may be grounded if not needed.

Table 8. DDRCLK AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} of 3.3V ± 5%.

Parameter/Condition	Symbol	Min	Typical	Max	Unit	Notes
DDRCLK jitter	—	—	—	+/– 150	ps	4, 5, 6

Notes:

1. **Caution:** The DDR complex clock to DDRCLK ratio settings must be chosen such that the resulting DDR complex clock frequency does not exceed the maximum or minimum operating frequencies. Refer to Section 19.4, “DDR/DDRCLK PLL Ratio,” for ratio settings.
2. Rise and fall times for DDRCLK are measured at 0.6 V and 2.7 V.
3. Timing is guaranteed by design and characterization.
4. This represents the total input jitter—short term and long term—and is guaranteed by design.
5. The DDRCLK driver’s closed loop jitter bandwidth should be <500 kHz at –20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track DDRCLK drivers with the specified jitter.
6. For spread spectrum clocking, guidelines are +0% to –1% down spread at a modulation rate between 20 kHz and 60 kHz on DDRCLK.

4.5 Platform to eTSEC FIFO Restrictions

Note the following eTSEC FIFO mode maximum speed restrictions based on platform (CCB) frequency.

For FIFO GMII modes (both 8 and 16 bit) and 16-bit encoded FIFO mode:

> FIFO TX/RX clock frequency <= platform clock (CCB) frequency/4.2
>
> For example, if the platform (CCB) frequency is 533 MHz, the FIFO TX/RX clock frequency should be no more than 127 MHz.

For 8-bit encoded FIFO mode:

> FIFO TX/RX clock frequency <= platform clock (CCB) frequency/3.2
>
> For example, if the platform (CCB) frequency is 533 MHz, the FIFO TX/RX clock frequency should be no more than 167 MHz.

4.6 Other Input Clocks

For information on the input clocks of other functional blocks of the platform, such as SerDes and eTSEC, see the respective sections of this document.

5 RESET Initialization

Table 9 describes the AC electrical specifications for the RESET initialization timing.

Table 9. RESET Initialization Timing Specifications

Parameter/Condition	Min	Max	Unit	Notes
Required assertion time of $\overline{\text{HRESET}}$	100	—	µs	2
Minimum assertion time for $\overline{\text{SRESET}}$	3	—	SYSCLKs	1

Table 11. DDR2 SDRAM Interface DC Electrical Characteristics for GV_{DD}(typ) = 1.8 V (continued)

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Output low current (V_{OUT} = 0.280 V)	I_{OL}	13.4	—	mA	—

Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. $MV_{REF}n$ is expected to be equal to 0.5 × GV_{DD}, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on $MV_{REF}n$ may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to that far end signal termination is made and is expected to be equal to $MV_{REF}n$. This rail should track variations in the DC level of $MV_{REF}n$.
4. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ GV_{DD}.

Table 12 provides the recommended operating conditions for the DDR SDRAM controller of the MPC8572E when interfacing to DDR3 SDRAM.

Table 12. DDR3 SDRAM Interface DC Electrical Characteristics for GV_{DD}(typ) = 1.5 V

Parameter/Condition	Symbol	Min	Typical	Max	Unit
I/O supply voltage	GV_{DD}	1.425	1.575	V	1
I/O reference voltage	$MV_{REF}n$	0.49 × GV_{DD}	0.51 × GV_{DD}	V	2
Input high voltage	V_{IH}	$MV_{REF}n$ + 0.100	GV_{DD}	V	—
Input low voltage	V_{IL}	GND	$MV_{REF}n$ – 0.100	V	—
Output leakage current	I_{OZ}	–50	50	µA	3

Notes:

1. GV_{DD} is expected to be within 50 mV of the DRAM GV_{DD} at all times.
2. $MV_{REF}n$ is expected to be equal to 0.5 × GV_{DD}, and to track GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on $MV_{REF}n$ may not exceed ±1% of the DC value.
3. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ GV_{DD}.

Table 13 provides the DDR SDRAM controller interface capacitance for DDR2 and DDR3.

Table 13. DDR2 and DDR3 SDRAM Interface Capacitance for GV_{DD}(typ)=1.8 V and 1.5 V

Parameter/Condition	Symbol	Min	Typical	Max	Unit
Input/output capacitance: DQ, DQS, $\overline{DQS}$	C_{IO}	6	8	pF	1, 2
Delta input/output capacitance: DQ, DQS, $\overline{DQS}$	C_{DIO}	—	0.5	pF	1, 2

Note:

1. This parameter is sampled. GV_{DD} = 1.8 V ± 0.090 V (for DDR2), f = 1 MHz, T_A = 25°C, V_{OUT} = GV_{DD}/2, V_{OUT} (peak-to-peak) = 0.2 V.
2. This parameter is sampled. GV_{DD} = 1.5 V ± 0.075 V (for DDR3), f = 1 MHz, T_A = 25°C, V_{OUT} = GV_{DD}/2, V_{OUT} (peak-to-peak) = 0.175 V.

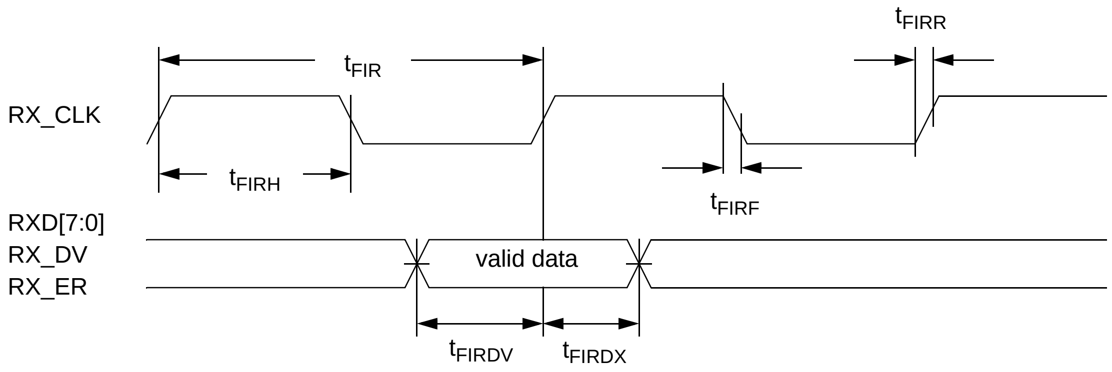


Figure 8. FIFO Receive AC Timing Diagram

8.2.2 GMII AC Timing Specifications

This section describes the GMII transmit and receive AC timing specifications.

8.2.2.1 GMII Transmit AC Timing Specifications

Table 27 provides the GMII transmit AC timing specifications.

Table 27. GMII Transmit AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit
GMII data TXD[7:0], TX_ER, TX_EN setup time	t_{GTKHDV}	2.5	—	—	ns
GTX_CLK to GMII data TXD[7:0], TX_ER, TX_EN delay	t_{GTKHDX}	0.5	—	5.0	ns
GTX_CLK data clock rise time (20%-80%)	t_{GTXR}[2]	—	—	1.0	ns
GTX_CLK data clock fall time (80%-20%)	t_{GTXF}[2]	—	—	1.0	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{GTKHDV} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) reaching the valid state (V) to state or setup time. Also, t_{GTKHDX} symbolizes GMII transmit timing (GT) with respect to the t_{GTX} clock reference (K) going to the high state (H) relative to the time date input signals (D) going invalid (X) or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GTX} represents the GMII(G) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. Guaranteed by design.

Figure 15 shows the TBI transmit AC timing diagram.

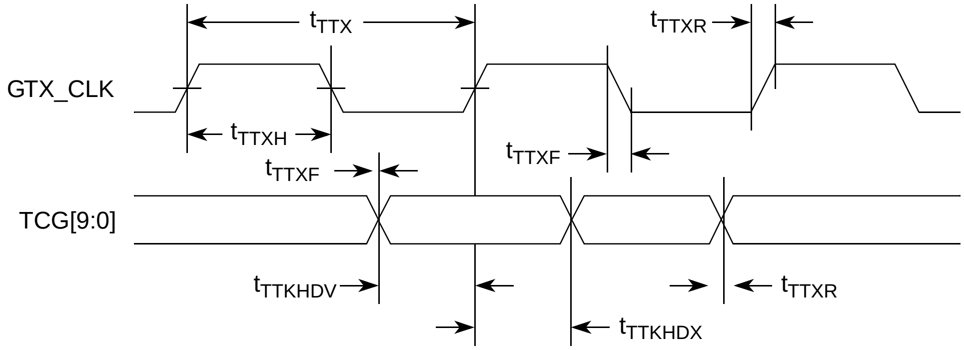


Figure 15. TBI Transmit AC Timing Diagram

8.2.4.2 TBI Receive AC Timing Specifications

Table 32 provides the TBI receive AC timing specifications.

Table 32. TBI Receive AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 2.5/ 3.3 V ± 5%.

Parameter/Condition [3]	Symbol [1]	Min	Typ	Max	Unit
Clock period for TBI Receive Clock 0, 1	t_{TRX}	—	16.0	—	ns
Skew for TBI Receive Clock 0, 1	t_{SKTRX}	7.5	—	8.5	ns
Duty cycle for TBI Receive Clock 0, 1	t_{TRXH}/t_{TRX}	40	—	60	%
RCG[9:0] setup time to rising edge of TBI Receive Clock 0, 1	t_{TRDVKH}	2.5	—	—	ns
RCG[9:0] hold time to rising edge of TBI Receive Clock 0, 1	t_{TRDXKH}	1.5	—	—	ns
Clock rise time (20%-80%) for TBI Receive Clock 0, 1	t_{TRXR}[2]	0.7	—	2.4	ns
Clock fall time (80%-20%) for TBI Receive Clock 0, 1	t_{TRXF}[2]	0.7	—	2.4	ns

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{TRDVKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{TRX} clock reference (K) going to the high (H) state or setup time. Also, t_{TRDXKH} symbolizes TBI receive timing (TR) with respect to the time data input signals (D) went invalid (X) relative to the t_{TRX} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{TRX} represents the TBI (T) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall). For symbols representing skews, the subscript is skew (SK) followed by the clock that is being skewed (TRX).
2. Guaranteed by design.
3. The signals “TBI Receive Clock 0” and “TBI Receive Clock 1” refer to TSECn_RX_CLK and TSECn_TX_CLK pins respectively. These two clock signals are also referred as PMA_RX_CLK[0:1].

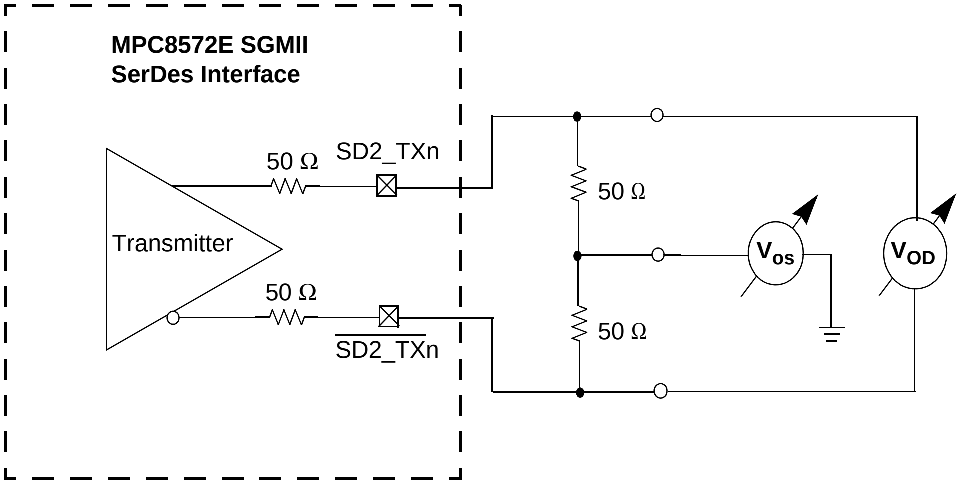


Figure 23. SGMII Transmitter DC Measurement Circuit

Table 39 lists the SGMII DC receiver electrical characteristics.

Table 39. SGMII DC Receiver Electrical Characteristics

Parameter		Symbol	Min	Typ	Max	Unit	Notes
Supply Voltage		XV_{DD_SRDS2}	1.045	1.1	1.155	V	—
DC Input voltage range		—	N/A			—	1
Input differential voltage	LSTS = 0	$V_{RX\_DIFFp-p}$	100	—	1200	mV	2, 4
	LSTS = 1		175	—			
Loss of signal threshold	LSTS = 0	VLOS	30	—	100	mV	3, 4
	LSTS = 1		65	—	175		
Input AC common mode voltage		V_{CM_ACp-p}		—	100	mV	5
Receiver differential input impedance		Z_{RX_DIFF}	80	100	120	Ω	—
Receiver common mode input impedance		Z_{RX_CM}	20	—	35	Ω	—
Common mode input voltage		V_{CM}	—	$V_{xcorevss}$	—	V	6

Note:

1. Input must be externally AC-coupled.
2. $V_{RX\_DIFFp-p}$ is also referred to as peak to peak input differential voltage
3. The concept of this parameter is equivalent to the Electrical Idle Detect Threshold parameter in PCI Express. Refer to PCI Express Differential Receiver (RX) Input Specifications section for further explanation.
4. The LSTS shown in the table refers to the LSTS**AB** or LSTS**EF** bit field of MPC8572E's SerDes 2 Control Register.
5. V_{CM_ACp-p} is also referred to as peak to peak AC common mode voltage.
6. On-chip termination to SGND_SRDS2 (xcorevss).

8.4 eTSEC IEEE Std 1588™ AC Specifications

Figure 26 shows the data and command output timing diagram.

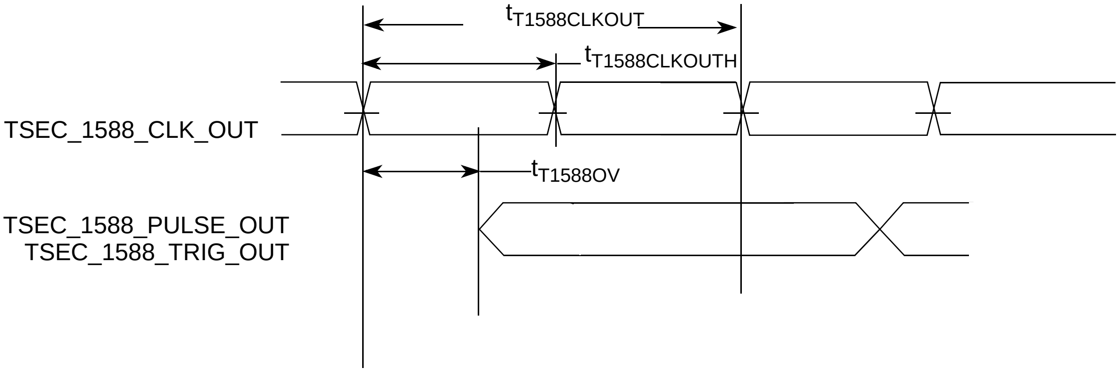


Figure 26. eTSEC IEEE 1588 Output AC Timing

[1] The output delay is count starting rising edge if $t_{T1588CLKOUT}$ is non-inverting. Otherwise, it is count starting falling edge.

Figure 27 shows the data and command input timing diagram.

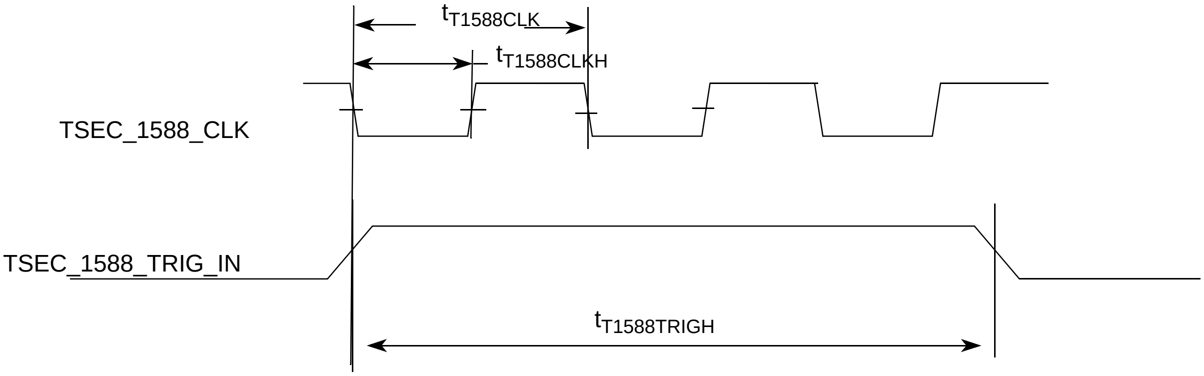


Figure 27. eTSEC IEEE 1588 Input AC timing

Table 42 provides the IEEE 1588 AC timing specifications.

Table 42. eTSEC IEEE 1588 AC Timing Specifications

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
TSEC_1588_CLK clock period	$t_{T1588CLK}$	3.3	—	T_{TX_CLK}*9	ns	1
TSEC_1588_CLK duty cycle	$t_{T1588CLKH}$ /$t_{T1588CLK}$	40	50	60	%	—
TSEC_1588_CLK peak-to-peak jitter	$t_{T1588CLKINJ}$	—	—	250	ps	—
Rise time eTSEC_1588_CLK (20%–80%)	$t_{T1588CLKINR}$	1.0	—	2.0	ns	—
Fall time eTSEC_1588_CLK (80%–20%)	$t_{T1588CLKINF}$	1.0	—	2.0	ns	—
TSEC_1588_CLK_OUT clock period	$t_{T1588CLKOUT}$	2*$t_{T1588CLK}$	—	—	ns	—

Table 42. eTSEC IEEE 1588 AC Timing Specifications (continued)

At recommended operating conditions with LV_{DD}/TV_{DD} of 3.3 V ± 5% or 2.5 V ± 5%

Parameter/Condition	Symbol	Min	Typ	Max	Unit	Note
TSEC_1588_CLK_OUT duty cycle	$t_{T1588CLKOTH}$ $/t_{T1588CLKOUT}$	30	50	70	%	—
TSEC_1588_PULSE_OUT	$t_{T1588OV}$	0.5	—	3.0	ns	—
TSEC_1588_TRIG_IN pulse width	$t_{T1588TRIGH}$	$2{*}t_{T1588CLK\_MAX}$	—	—	ns	2

Note:

1. When TMR_CTRL[CKSEL] is set as '00', the external TSEC_1588_CLK input is selected as the 1588 timer reference clock source, with the timing defined in Table 42, "eTSEC IEEE 1588 AC Timing Specifications." The maximum value of $t_{T1588CLK}$ is defined in terms of T_{TX_CLK}, that is the maximum clock cycle period of the equivalent interface speed that the eTSEC1 port is running at. When eTSEC1 is configured to operate in the parallel mode, the T_{TX_CLK} is the maximum clock period of the TSEC1_TX_CLK. When eTSEC1 operates in SGMII mode, the maximum value of $t_{T1588CLK}$ is defined in terms of the recovered clock from SGMII SerDes. For example, for SGMII 10/100/1000 Mbps modes, the maximum value of $t_{T1588CLK}$ is 3600, 360, 72 ns respectively. See the *MPC8572E PowerQUICC™ III Integrated Communications Processor Reference Manual* for detailed description of TMR_CTRL registers.
2. It needs to be at least two times of the clock period of the clock selected by TMR_CTRL[CKSEL].

9 Ethernet Management Interface Electrical Characteristics

The electrical characteristics specified here apply to MII management interface signals ECn_MDIO (management data input/output) and ECn_MDC (management data clock). The electrical characteristics for GMII, SGMII, RGMII, RMII, TBI and RTBI are specified in "Section 8, "Ethernet: Enhanced Three-Speed Ethernet (eTSEC).""

9.1 MII Management DC Electrical Characteristics

The ECn_MDC and ECn_MDIO are defined to operate at a supply voltage of 3.3 V or 2.5 V. The DC electrical characteristics for ECn_MDIO and ECn_MDC are provided in Table 43 and Table 44.

Table 43. MII Management DC Electrical Characteristics (LV_{DD}/TV_{DD}=3.3 V)

Parameter	Symbol	Min	Max	Unit	Notes
Supply voltage (3.3 V)	LV_{DD}/TV_{DD}	3.13	3.47	V	1, 2
Output high voltage (LV_{DD}/TV_{DD} = Min, I_{OH} = –1.0 mA)	V_{OH}	2.10	OV_{DD} + 0.3	V	—
Output low voltage (LV_{DD}/TV_{DD} =Min, I_{OL} = 1.0 mA)	V_{OL}	GND	0.50	V	—
Input high voltage	V_{IH}	2.0	—	V	—
Input low voltage	V_{IL}	—	0.90	V	—
Input high current (LV_{DD}/TV_{DD} = Max, V_{IN} ^{3} = 2.1 V)	I_{IH}	—	40	µA	—

Figure 30 through Figure 35 show the local bus signals.

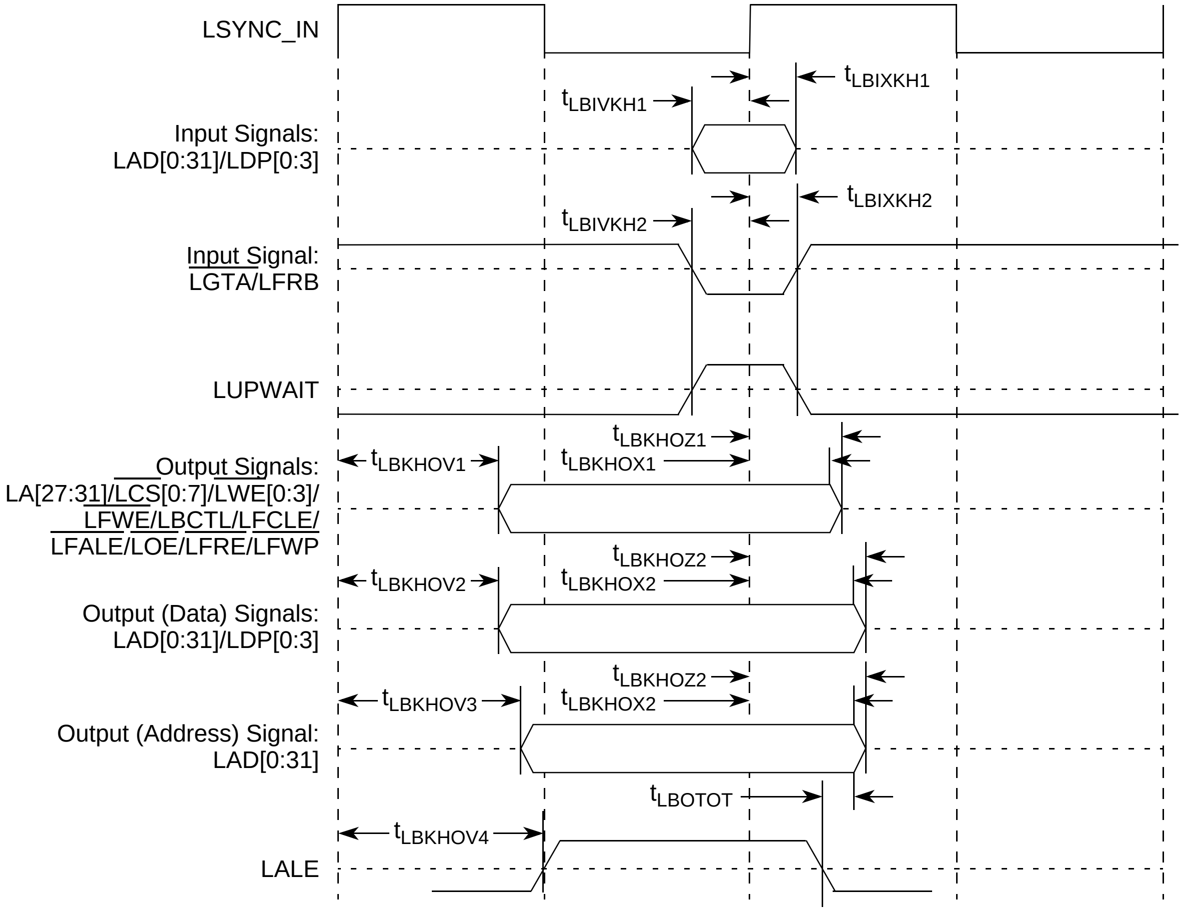


Figure 30. Local Bus Signals, Non-Special Signals Only (PLL Enabled)

Table 52 describes the general timing parameters of the local bus interface at BV_{DD} = 3.3 V DC with PLL disabled.

Table 52. Local Bus General Timing Parameters—PLL Bypassed

At recommended operating conditions with BV_{DD} of 3.3 V ± 5%

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus cycle time	t_{LBK}	12	—	ns	2
Local bus duty cycle	t_{LBKH}/t_{LBK}	43	57	%	—
Internal launch/capture clock to LCLK delay	t_{LBKHKT}	2.3	4.0	ns	—
Input setup to local bus clock (except LGTA/LUPWAIT)	$t_{LBIVKH1}$	5.8	—	ns	4, 5
LGTA/LUPWAIT input setup to local bus clock	$t_{LBIVKL2}$	5.7	—	ns	4, 5
Input hold from local bus clock (except LGTA/LUPWAIT)	$t_{LBIXKH1}$	-1.3	—	ns	4, 5

Table 54. I^2C DC Electrical Characteristics (continued)

Capacitance for each I/O pin	C_I	—	10	pF	—

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.
2. Refer to the *MPC8572E PowerQUICC™ III Integrated Host Processor Family Reference Manual* for information on the digital filter used.
3. I/O pins will obstruct the SDA and SCL lines if OV_{DD} is switched off.

13.2 I^2C AC Electrical Specifications

Table 55 provides the AC timing parameters for the I^2C interfaces.

Table 55. I^2C AC Electrical Specifications

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%. All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 2).

Parameter	Symbol[1]	Min	Max	Unit
SCL clock frequency	f_{I2C}	0	400	kHz[4]
Low period of the SCL clock	t_{I2CL}	1.3	—	µs
High period of the SCL clock	t_{I2CH}	0.6	—	µs
Setup time for a repeated START condition	t_{I2SVKH}	0.6	—	µs
Hold time (repeated) START condition (after this period, the first clock pulse is generated)	t_{I2SXKL}	0.6	—	µs
Data setup time	t_{I2DVKH}	100	—	ns
Data input hold time: CBUS compatible masters I^2C bus devices	t_{I2DXKL}	 — 0[2]	 — —	µs
Data output delay time	t_{I2OVKL}	—	0.9[3]	µs
Setup time for STOP condition	t_{I2PVKH}	0.6	—	µs
Bus free time between a STOP and START condition	t_{I2KHDX}	1.3	—	µs
Noise margin at the LOW level for each connected device (including hysteresis)	V_{NL}	$0.1 \times OV_{DD}$	—	V
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V

clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.

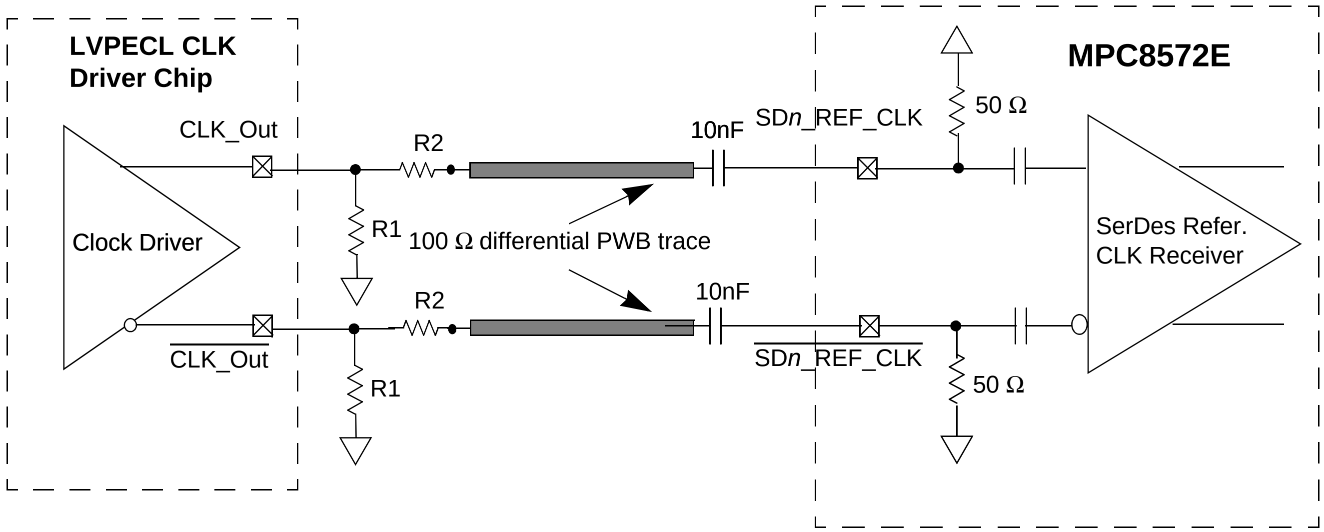


Figure 50. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

Figure 51 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with MPC8572E SerDes reference clock input’s DC requirement.

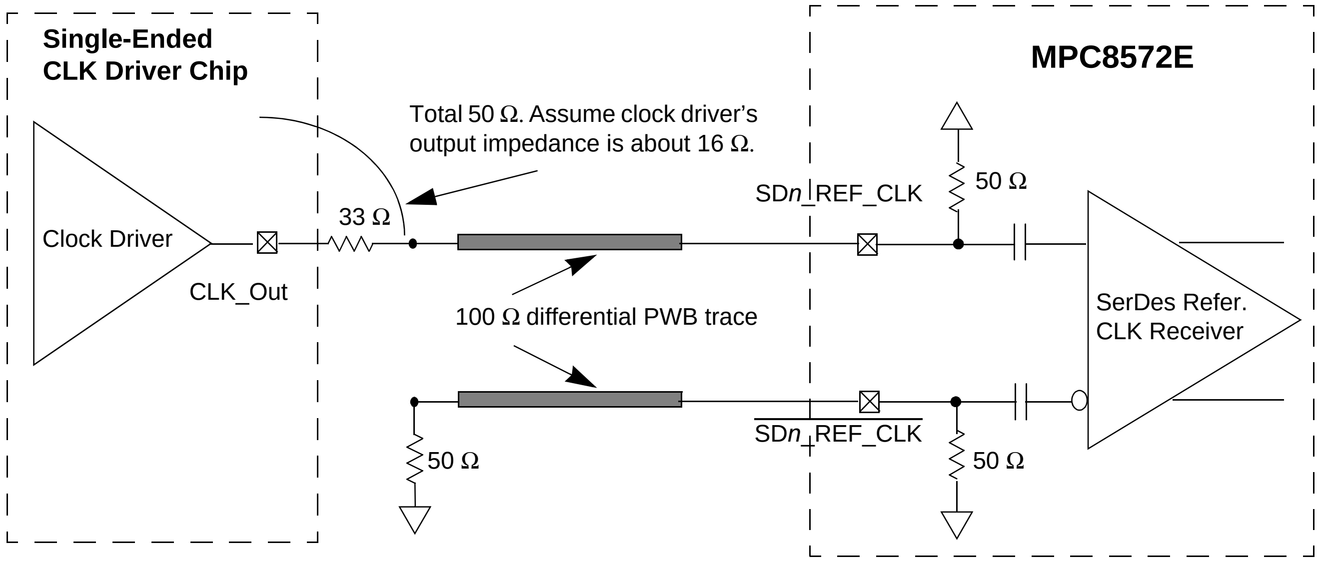


Figure 51. Single-Ended Connection (Reference Only)

15.2.4 AC Requirements for SerDes Reference Clocks

The clock driver selected should provide a high quality reference clock with low phase noise and cycle-to-cycle jitter. Phase noise less than 100KHz can be tracked by the PLL and data recovery loops and

Table 63. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nominal	Max	Units	Comments
$T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$	Maximum time between the jitter median and maximum deviation from the median.	—	—	0.3	UI	Jitter is defined as the measurement variation of the crossing points ($V_{RX\text{-}DIFFp\text{-}p}$ = 0 V) in relation to a recovered TX UI. A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. Jitter is measured using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI. See Notes 2, 3 and 7.
$V_{RX\text{-}CM\text{-}ACp}$	AC Peak Common Mode Input Voltage	—	—	150	mV	$V_{RX\text{-}CM\text{-}ACp} = \|V_{RXD+} + V_{RXD-}\|/2 - V_{RX\text{-}CM\text{-}DC}$ $V_{RX\text{-}CM\text{-}DC} = DC_{(avg)}$ of $\|V_{RX\text{-}D+} + V_{RX\text{-}D-}\|/2$ See Note 2
$RL_{RX\text{-}DIFF}$	Differential Return Loss	15	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at +300 mV and -300 mV, respectively. See Note 4
$RL_{RX\text{-}CM}$	Common Mode Return Loss	6	—	—	dB	Measured over 50 MHz to 1.25 GHz with the D+ and D- lines biased at 0 V. See Note 4
$Z_{RX\text{-}DIFF\text{-}DC}$	DC Differential Input Impedance	80	100	120	Ω	RX DC Differential mode impedance. See Note 5
$Z_{RX\text{-}DC}$	DC Input Impedance	40	50	60	Ω	Required RX D+ as well as D- DC Impedance (50 ± 20% tolerance). See Notes 2 and 5.
$Z_{RX\text{-}HIGH\text{-}IMP\text{-}DC}$	Powered Down DC Input Impedance	200 k	—	—	Ω	Required RX D+ as well as D- DC Impedance when the Receiver terminations do not have power. See Note 6.
$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$	Electrical Idle Detect Threshold	65	—	175	mV	$V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p} = 2^*\|V_{RX\text{-}D+} - V_{RX\text{-}D-}\|$ Measured at the package pins of the Receiver
$T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERTIME}$	Unexpected Electrical Idle Enter Detect Threshold Integration Time	—	—	10	ms	An unexpected Electrical Idle ($V_{RX\text{-}DIFFp\text{-}p} < V_{RX\text{-}IDLE\text{-}DET\text{-}DIFFp\text{-}p}$) must be recognized no longer than $T_{RX\text{-}IDLE\text{-}DET\text{-}DIFF\text{-}ENTERING}$ to signal an unexpected idle condition.

Table 63. Differential Receiver (RX) Input Specifications (continued)

Symbol	Parameter	Min	Nominal	Max	Units	Comments
$L_{RX\text{-}SKEW}$	Total Skew	—	—	20	ns	Skew across all lanes on a Link. This includes variation in the length of SKP ordered set (for example, COM and one to five SKP Symbols) at the RX as well as any delay differences arising from the interconnect itself.

Notes:

1. No test load is necessarily associated with this value.
2. Specified at the measurement point and measured over any 250 consecutive UIs. The test load in Figure 57 should be used as the RX device when taking measurements (also refer to the Receiver compliance eye diagram shown in Figure 56). If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as a reference for the eye diagram.
3. A $T_{RX\text{-}EYE}$ = 0.40 UI provides for a total sum of 0.60 UI deterministic and random jitter budget for the Transmitter and interconnect collected any 250 consecutive UIs. The $T_{RX\text{-}EYE\text{-}MEDIAN\text{-}to\text{-}MAX\text{-}JITTER}$ specification ensures a jitter distribution in which the median and the maximum deviation from the median is less than half of the total. UI jitter budget collected over any 250 consecutive TX UIs. It should be noted that the median is not the same as the mean. The jitter median describes the point in time where the number of jitter points on either side is approximately equal as opposed to the averaged time value. If the clocks to the RX and TX are not derived from the same reference clock, the TX UI recovered from 3500 consecutive UI must be used as the reference for the eye diagram.
4. The Receiver input impedance shall result in a differential return loss greater than or equal to 15 dB with the D+ line biased to 300 mV and the D- line biased to -300 mV and a common mode return loss greater than or equal to 6 dB (no bias required) over a frequency range of 50 MHz to 1.25 GHz. This input impedance requirement applies to all valid input levels. The reference impedance for return loss measurements for is 50 ohms to ground for both the D+ and D- line (that is, as measured by a Vector Network Analyzer with 50 ohm probes - see Figure 57). Note: that the series capacitors CTX is optional for the return loss measurement.
5. Impedance during all LTSSM states. When transitioning from a Fundamental Reset to Detect (the initial state of the LTSSM) there is a 5 ms transition time before Receiver termination values must be met on all un-configured Lanes of a Port.
6. The RX DC Common Mode Impedance that exists when no power is present or Fundamental Reset is asserted. This helps ensure that the Receiver Detect circuit does not falsely assume a Receiver is powered on when it is not. This term must be measured at 300 mV above the RX ground.
7. It is recommended that the recovered TX UI is calculated using all edges in the 3500 consecutive UI interval with a fit algorithm using a minimization merit function. Least squares and median deviation fits have worked well with experimental and simulated data.

17.1 DC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

For more information, see Section 15.2, “SerDes Reference Clocks.”

17.2 AC Requirements for Serial RapidIO SD1_REF_CLK and SD1_REF_CLK

Figure 64lists the AC requirements.

Table 64. SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ AC Requirements

Symbol	Parameter Description	Min	Typical	Max	Units	Comments
t_{REF}	REFCLK cycle time	—	10(8)	—	ns	8 ns applies only to serial RapidIO with 125-MHz reference clock
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	80	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	–40	—	40	ps	—

17.3 Equalization

With the use of high speed serial links, the interconnect media causes degradation of the signal at the receiver. Effects such as Inter-Symbol Interference (ISI) or data dependent jitter are produced. This loss can be large enough to degrade the eye opening at the receiver beyond what is allowed in the specification. To negate a portion of these effects, equalization can be used. The most common equalization techniques that can be used are as follows:

- A passive high pass filter network placed at the receiver. This is often referred to as passive equalization.
- The use of active circuits in the receiver. This is often referred to as adaptive equalization.

17.4 Explanatory Note on Transmitter and Receiver Specifications

AC electrical specifications are given for transmitter and receiver. Long run and short run interfaces at three baud rates (a total of six cases) are described.

The parameters for the AC electrical specifications are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002.

XAUI has similar application goals to serial RapidIO, as described in Section 8.1, “Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—FIFO/GMII/MII/TBI/RGMII/RTBI/RMII Electrical Characteristics.” The goal of this standard is that electrical designs for Serial RapidIO can reuse electrical designs for XAUI, suitably modified for applications at the baud intervals and reaches described herein.

Table 74. Receiver AC Timing Specifications—3.125 GBaud

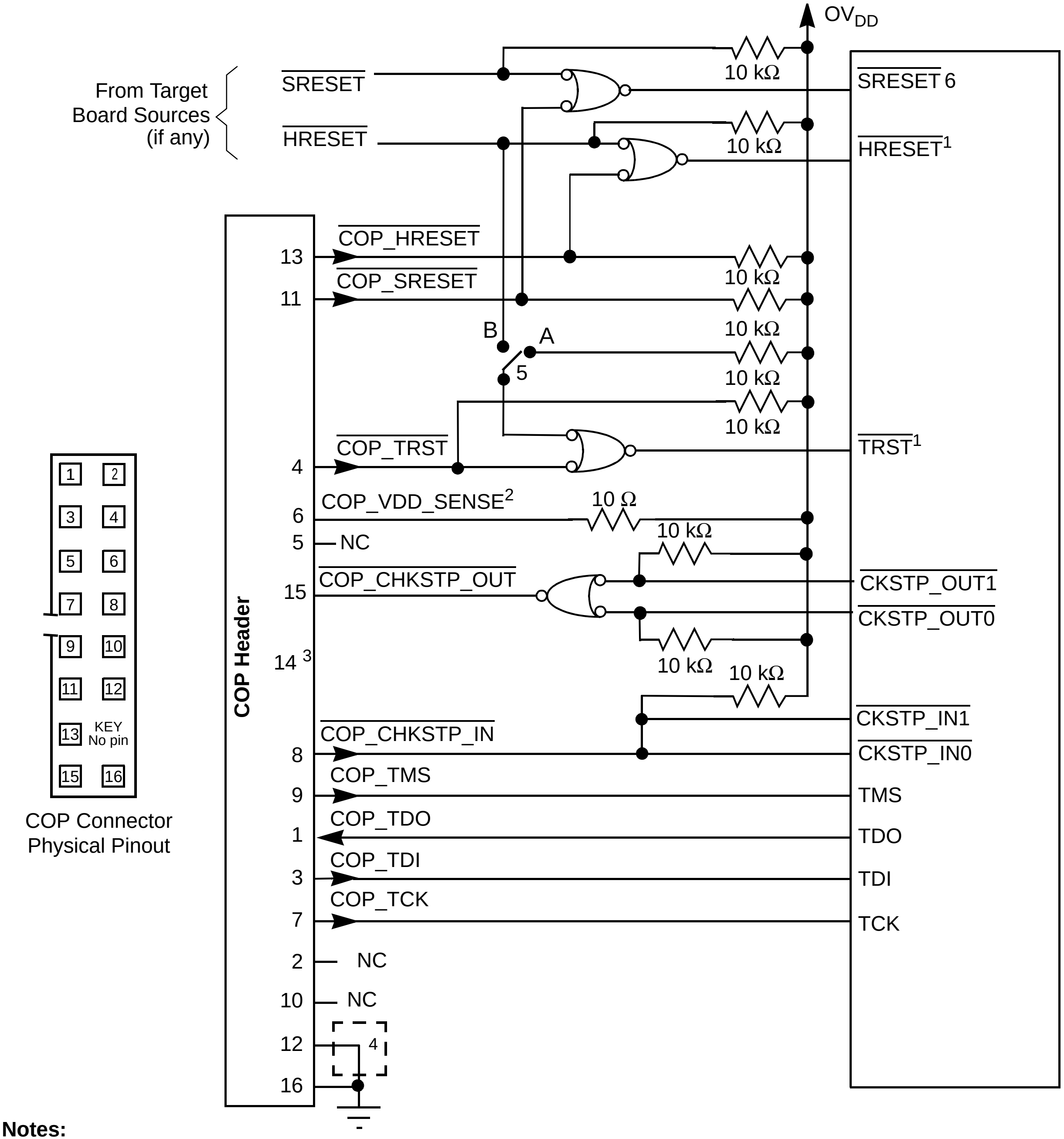
Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Differential Input Voltage	V_{IN}	200	1600	mV p-p	Measured at receiver
Deterministic Jitter Tolerance	J_D	0.37	—	UI p-p	Measured at receiver
Combined Deterministic and Random Jitter Tolerance	J_{DR}	0.55	—	UI p-p	Measured at receiver
Total Jitter Tolerance[1]	J_T	0.65	—	UI p-p	Measured at receiver
Multiple Input Skew	S_{MI}	—	22	ns	Skew at the receiver input between lanes of a multilane link
Bit Error Rate	BER	—	10^{-12}	—	—
Unit Interval	UI	320	320	ps	+/- 100 ppm

Note:

1. Total jitter is composed of three components, deterministic jitter, random jitter and single frequency sinusoidal jitter. The sinusoidal jitter may have any amplitude and frequency in the unshaded region of Figure 59. The sinusoidal jitter component is included to ensure margin for low frequency jitter, wander, noise, crosstalk and other variable system effects.

Table 76. MPC8572E Pinout Listing (continued)

Signal	Signal Name	Package Pin Number	Pin Type	Power Supply	Notes
SD1_IMP_CAL_RX	SerDes1 Rx Impedance Calibration	B32	I	200Ω (±1%) to GND	—
SD1_IMP_CAL_TX	SerDes1 Tx Impedance Calibration	T32	I	100Ω (±1%) to GND	—
SD1_PLL_TPA	SerDes1 PLL Test Point Analog	J30	O	AVDD_SRDS analog	17
SD2_IMP_CAL_RX	SerDes2 Rx Impedance Calibration	AC32	I	200Ω (±1%) to GND	—
SD2_IMP_CAL_TX	SerDes2 Tx Impedance Calibration	AM32	I	100Ω (±1%) to GND	—
SD2_PLL_TPA	SerDes2 PLL Test Point Analog	AH30	O	AVDD_SRDS analog	17
TEMP_ANODE	Temperature Diode Anode	AA31	—	internal diode	14
TEMP_CATHODE	Temperature Diode Cathode	AB31	—	internal diode	14
No Connection Pins					



Notes:

1. The COP port and target board should be able to independently assert $\overline{\text{HRESET}}$ and $\overline{\text{TRST}}$ to the processor to fully control the processor as shown here.
2. Populate this with a 10 Ω resistor for short-circuit/current-limiting protection.
3. The KEY location (pin 14) is not physically present on the COP header.
4. Although pin 12 is defined as a No-Connect, some debug tools may use pin 12 as an additional GND pin for improved signal integrity.
5. This switch is included as a precaution for BSDL testing. The switch should be closed to position A during BSDL testing to avoid accidentally asserting the $\overline{\text{TRST}}$ line. If BSDL testing is not being performed, this switch should be closed to position B.
6. Asserting $\overline{\text{SRESET}}$ causes a machine check interrupt to the e500 cores.

Table 90. Document Revision History (continued)

Rev. Number	Date	Substantive Change(s)
6	06/2014	• Updated Table 76, “MPC8572E Pinout Listing,” TDO signal is not driven during HRSET* assertion. • In Table 86, “Part Numbering Nomenclature—Rev 2.2.1,“ added full Pb-free part code.
5	01/2011	• Editorial changes throughout • Updated Table 4, “MPC8572E Power Dissipation,” to include low power product. • In Section 22.1, “Part Numbers Fully Addressed by this Document,” defined PPC as “Prototype” and changed table headings to say “Package Sphere Type”. • Added Table 86, “Part Numbering Nomenclature—Rev 2.2.1.”
4	06/2010	• In Section 18.3, “Pinout Listings,” updated Table 76 showing GPINOUT power rail as BVDD. • Updated Section 14.1, “GPIO DC Electrical Characteristics.”
3	03/2010	• In Section 2.1, “Overall DC Electrical Characteristics,” changed GPIO power from OVDD to BVDD. • In Section 22.1, “Part Numbers Fully Addressed by this Document,” added Table 87 for Rev 2.1 silicon. • In Section 22.1, “Part Numbers Fully Addressed by this Document,” updated Table 88 for Rev 1.1.1 silicon.
2	06/2009	• In Section 3, “Power Characteristics,” updated CCB Max to 533MHz for 1200MHz core device in Table 5, “MPC8572EL Power Dissipation.” • In Section 4.4, “DDR Clock Timing,” changed DDRCLK Max to 100MHz. This change was announced in Product Bulletin #13572. • Clarified restrictions in Section 4.5, “Platform to eTSEC FIFO Restrictions.” • In Table 9, “RESET Initialization Timing Specifications,” added note 2. • Added Section 14, “GPIO.” • In Section 18.1, “Package Parameters for the MPC8572E FC-PBGA,” updated material composition to 63% Sn, 37% Pb. • In Section 18.2, “Mechanical Dimensions of the MPC8572E FC-PBGA, updated Figure 61 to correct the package thickness and top view. • In Section 19.1, “Clock Ranges,” updated CCB Max to 533MHz for 1200MHz core device in Table 77, “MPC8572E Processor Core Clocking Specifications.” • In Section 19.5.2, “Minimum Platform Frequency Requirements for High-Speed Interfaces,” changed minimum CCB clock frequency for proper PCI Express operation. • Added LPBSE to description of LGPL4/LGTA/LUPWAIT/LPBSE/LFRB signal in Table 76, “MPC8572E Pinout Listing.” • Corrected supply voltage for GPIO pins in Table 76, “MPC8572E Pinout Listing.” • Applied note to SD1_PLL_TPA in Table 76, “MPC8572E Pinout Listing.” • Updated note regarding MDIC in Table 76, “MPC8572E Pinout Listing.” • Added note for LAD pins in Table 76, “MPC8572E Pinout Listing.” • Updated Table 88, “,Part Numbering Nomenclature—Rev 1.1.1” with Rev 2.0 and Rev 2.1 part number information. Added note indicating that silicon version 2.0 is available for prototype purposes only and will not be available as a qualified device.
1	08/2008	• In Section 22.1, “Part Numbers Fully Addressed by this Document,” added SVR information in, Table 88 “Part Numbering Nomenclature—Rev 1.1.1,” for devices without Security Engine feature.
0	07/2008	• Initial release.